

# FTP05N06N

Lead Free Package and Finish

R<sub>DS(ON)</sub>(Typ.)

3.1mΩ

G

TO-220

Packages Not to Scale I<sub>D (Silicon</sub>

limited current)

150A

D

S

# N-Channel MOSFET

#### **Applications:**

- Adaptor
- Charger
- .SMPS

#### Features:

- RoHS Compliant
- . Low ON Resistance
- . Low Gate Charge
- Peak Current vs Pulse Width Curve
- Inductive Switching Curves

#### **Ordering Information**

PART NUMBER	PACKAGE	BRAND
FTP05N06N	TO-220	IPS

#### **Absolute Maximum Ratings**

 $T_C=25^{\circ}C$  unless otherwise specified

Pb

 $V_{\text{DSS}}$ 

60V

Symbol	Parameter	FTP05N06N	Units
V <sub>DSS</sub>	Drain-to-Source Voltage	60	V
I <sub>D</sub>	Continuous Drain Current	150	А
	Continuous Drain Current $T_c = 100^{\circ}C$	95	А
I <sub>DM</sub>	Pulsed Drain Current (NOTE *1)	600	А
V <sub>GS</sub>	Gate-to-Source Voltage	±20	V
E <sub>AS</sub>	Single Pulse Avalanche Energy(NOTE *2)	1213	mJ
TL	Maximum Temperature for Soldering	300	
$T_{\rm J}$ and $T_{\rm STG}$	Operating Junction and Storage Temperature Range	150,-55 to150	°C

GDS



Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
BV <sub>DSS</sub>	Drain-to-Source Breakdown Voltage	60			V	V <sub>GS</sub> =0V, I <sub>D</sub> =250µA
I <sub>DSS</sub>				1	– μΑ	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V
	Drain-to-Source Leakage Current					T <sub>a</sub> =25℃
	Drain-to-Source Leakage Current			500		$V_{DS}$ =48V, $V_{GS}$ =0V
				500		T <sub>a</sub> =125℃
699	Gate-to-Source Forward Leakage			+100	n A	$V_{GS}$ =+20V
	Gate-to-Source Reverse Leakage			-100	nA	V <sub>GS</sub> = -20V

# **OFF Characteristics** $T_C=25^{\circ}C$ unless otherwise specified

#### **ON Characteristics** $T_J=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
R <sub>DS(ON)</sub>	StaticDrain-to-Source On-Resistance		3.1	4.5	mΩ	V <sub>GS</sub> =10V, I <sub>D</sub> =40A
V <sub>GS(TH)</sub>	Gate Threshold Voltage	2	3	4	V	$V_{DS}=V_{GS}$ , $I_{D}=250\mu$ A
Pulse width s	$\leqslant$ 300µs; duty cycle $\leqslant$ 2%					

# **Dynamic Characteristics** Essentially independent of operating temperature

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
Rg	Gate Resistance		0.9		Ω	f=1MHz, V <sub>GS</sub> =0V,
_						V <sub>DS</sub> =0V
C <sub>iss</sub>	Input Capacitance		4500			V <sub>GS</sub> = 0V,V <sub>DS</sub> = 25V f =1.0MHz
C <sub>oss</sub>	Output Capacitance		796		pF	
C <sub>rss</sub>	Reverse Transfer Capacitance		617			
Q <sub>g</sub>	Total Gate Charge		109.8			
Q <sub>gs</sub>	Gate-to-Source Charge		18.3		nC	$I_D=25A, V_{DD}=48V$ $V_{GS}=10V$
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge		49.8			$v_{GS} = 10v$

# **Resistive Switching Characteristics** Essentially independent of operating temperature

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
t <sub>d(ON)</sub>	Turn-on Delay Time		30.3			$V_{DD}$ =40V, $I_D$ =25A, $V_G$ =10V $R_G$ =6 $\Omega$
t <sub>rise</sub>	Rise Time		33.5			
t <sub>d(OFF)</sub>	Turn-Off Delay Time		87.2		ns	
t <sub>fall</sub>	Fall Time		49			



Source-Drain Diode Characteristics	Tc=25 $^{\circ}$ C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)			150	A	T 25°0
I <sub>SM</sub>	Maximum Pulsed Current (Body Diode)			600	А	T <sub>C</sub> =25℃
V <sub>SD</sub>	Diode Forward Voltage			1.2	V	I <sub>SD</sub> =30A, V <sub>GS</sub> =0V
t <sub>rr</sub>	Reverse Recovery Time		55.6		ns	I <sub>F</sub> =20A
Q <sub>rr</sub>	Reverse Recovery Charge		83.2		nC	di/dt=100A/us
Pulse width $\leq$ 300µs; duty cycle $\leq$ 2%						

Notes:

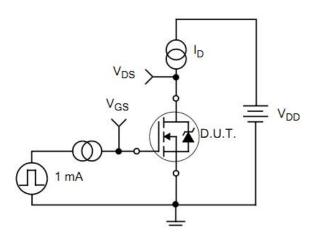
\*1. Repetitive rating; pulse width limited by maximum junction temperature.

\*2. L=0.5mH,  $I_D$ =69.7A, Start  $T_J$ =25 $^{\circ}$ C



### **Test Circuits and Waveforms**

Figure 14. Gate Charge Test Circuit



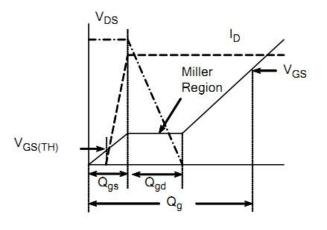
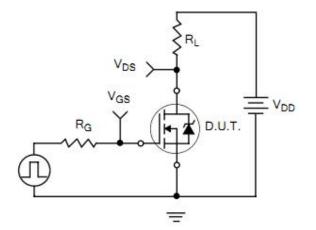
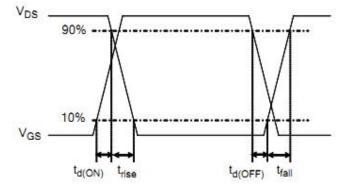


Figure 15. Gate Charge Waveforms

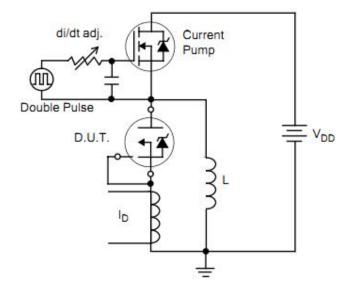
Figure 16. Resistive Switching Test Circuit

Figure 17. Resistive Switching Waveforms









#### Figure 18. Diode Reverse Recovery Test Circuit

Figure 19. Diode Reverse Recovery Waveform

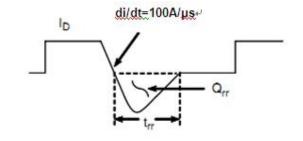
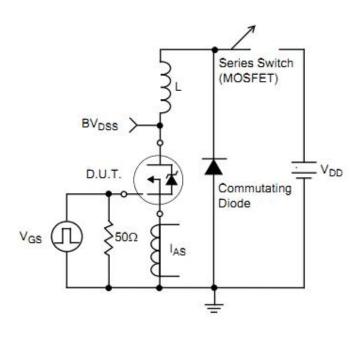
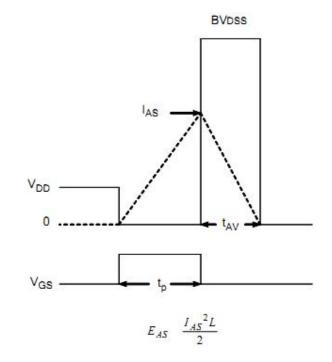


Figure20.Unclamped Inductive Switching Test Circuit

Figure21.Unclamped Inductive Switching Waveform







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  - b. support or sustain life,
  - c. whose failure to perform when properly used in accordance with instructions for used provided in the labeling, can be reasonably expected to result in significant injury to the user.

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